

**Notice of References Cited**Application/Control No.  
09/911,613Applicant(s)/Patent Under  
Reexamination  
CHUNG ET AL.Examiner  
A. SeferArt Unit  
2826

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,989,945 /	11-1999	Yudasaka et al	438/149
	B	US-6,081,310 /	06-2000	Katsuya et al	349/113
	C	US-6,323,521 /	11-2001	Seo	257/347
	D	US-6,358,759 /	03-2002	Hirabayashi	438/7
	E	US-2002/0106586 /	08-2002	You	430/311
	F	US-5,923,390 /	07-1999	Jung Mok et al	349/38
	G	US-5,917,563 /	06-1999	Matsushima	349/38
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11-87716 /	03-1999	Japan	Hidaka	
	O	JP 5-216069 /	08-1993	Japan	Koizumi et al	
	P	JP 10-90719 /	04-1998	Japan	Hioki et al	
	Q	JP 10-186412 /	07-1998	Japan	Yudasaka	
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.